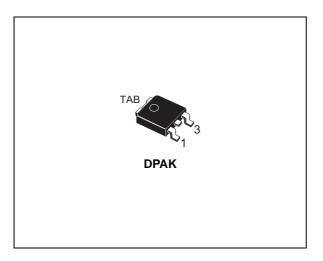


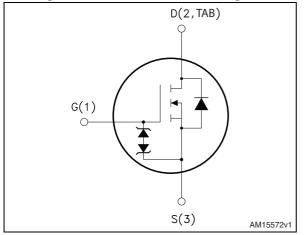
# STD9N40M2

Datasheet - preliminary data

### N-channel 400 V, 0.59 Ω typ., 6 A MDmesh II Plus<sup>™</sup> low Q<sub>g</sub> Power MOSFET in a DPAK package



#### Figure 1. Internal schematic diagram



#### Features

Order code	$\rm V_{DS} \ @ T_{Jmax}$	R <sub>DS(on)</sub> max	I <sub>D</sub>
STD9N40M2	450 V	0.8 Ω	6 A

- Extremely low gate charge
- Lower R<sub>DS(on)</sub> x area vs previous generation
- Low gate input resistance
- 100% avalanche tested
- Zener-protected

### **Applications**

• Switching applications

### Description

This device is an N-channel Power MOSFET developed using a new generation of MDmesh<sup>TM</sup> technology: MDmesh II Plus<sup>TM</sup> low  $Q_g$ . This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

#### Table 1. Device summary

Order code	Marking	Package	Packaging
STD9N40M2	9N40M2	DPAK	Tape and reel

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This is preliminary information on a new product now in development or undergoing evaluation. Details are subject to change without notice.

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## 1 Electrical ratings

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source voltage	400	V
V <sub>GS</sub>	Gate-source voltage	± 25	V
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 25 °C	6	Α
۱ <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 100 °C	3.8	Α
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	24	Α
P <sub>TOT</sub>	Total dissipation at $T_{C}$ = 25 °C	60	W
dv/dt <sup>(1)</sup>	Peak diode recovery voltage slope	15	V/ns
dv/dt <sup>(2)</sup>	MOSFET dv/dt ruggedness	50	v/115
T <sub>stg</sub>	Storage temperature	- 55 to 150	ာ
Τj	Max. operating junction temperature	- 55 10 150	C

#### Table 2. Absolute maximum ratings

1. I\_{SD}  $\leq$  6 A, di/dt  $\leq$  400 A/ $\mu$ s; V<sub>DS peak</sub> < V<sub>(BR)DSS</sub>, V<sub>DD</sub>=320 V

 $2. \quad V_{DS} \leq 320 \ V$ 

#### Table 3. Thermal data

Symbol	Value	Unit	
R <sub>thj-case</sub>	Thermal resistance junction-case max	2.08	°C/W
R <sub>thj-pcb</sub>	Thermal resistance junction-pcb max <sup>(1)</sup>	50	°C/W

1. When mounted on 1 inch<sup>2</sup> FR-4, 2 Oz copper board

#### Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or not repetitive (pulse width limited by T <sub>jmax</sub> )	2.5	А
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_j=25^{\circ}C$ , $I_D=I_{AR}$ , $V_{DD}=50$ )	148	mJ



### 2 Electrical characteristics

(T<sub>C</sub> = 25 °C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	V <sub>GS</sub> = 0, I <sub>D</sub> = 1 mA	400			V
	Zero gate voltage	$V_{GS} = 0, V_{DS} = 400 V$			1	μA
I <sub>DSS</sub>	drain current	V <sub>GS</sub> = 0, V <sub>DS</sub> = 400 V, T <sub>C</sub> =125 °C			100	μA
I <sub>GSS</sub>	Gate-body leakage current	V <sub>DS</sub> = 0, V <sub>GS</sub> = ± 25 V			±10	μA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2	3	4	V
R <sub>DS(on)</sub>	Static drain-source on-resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 3 A		0.59	0.8	Ω

#### Table 5. On /off states

#### Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub>	Input capacitance		-	270	-	pF
C <sub>oss</sub>	Output capacitance	$V_{GS} = 0, V_{DS} = 100 V,$	-	22	-	pF
C <sub>rss</sub>	Reverse transfer capacitance	if = 1 MHz	-	0.7	-	pF
C <sub>oss eq.</sub> <sup>(1)</sup>	Equivalent output capacitance	$V_{GS} = 0, V_{DS} = 0$ to 320 V	-	94	-	pF
R <sub>G</sub>	Intrinsic gate resistance	f = 1 MHz, I <sub>D</sub> =0	-	7.1	-	Ω
Qg	Total gate charge	V <sub>DD</sub> = 320 V, I <sub>D</sub> = 6 A,	-	8.8	-	nC
Q <sub>gs</sub>	Gate-source charge	V <sub>GS</sub> = 10 V	-	1.7	-	nC
Q <sub>gd</sub>	Gate-drain charge	(see Figure 15)	-	4.8	-	nC

1.  $C_{oss\;eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ 

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time		-	10.5	-	ns
t <sub>r</sub>	Rise time	V <sub>DD</sub> = 200 V, I <sub>D</sub> = 3 A, R <sub>G</sub> = 4.7 Ω, V <sub>GS</sub> = 10 V	-	9	-	ns
t <sub>d(off)</sub>	Turn-off delay time	$G_{G} = 4.7 \Omega, V_{GS} = 10 V$ (see <i>Figure 14</i> and <i>19</i> )	-	7.5	-	ns
t <sub>f</sub>	Fall time		-	21	-	ns



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		-		6	А
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		24	А
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	V <sub>GS</sub> = 0, I <sub>SD</sub> = 6 A	-		1.6	V
t <sub>rr</sub>	Reverse recovery time		-	208		ns
Q <sub>rr</sub>	Reverse recovery charge	I <sub>SD</sub> = 6 A, di/dt = 100 A/μs V <sub>DD</sub> = 60 V (see <i>Figure 16</i> )	-	1.2		μC
I <sub>RRM</sub>	Reverse recovery current		-	11.5		А
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 6 A, di/dt = 100 A/µs	-	264		ns
Q <sub>rr</sub>	Reverse recovery charge	V <sub>DD</sub> = 60 V, T <sub>j</sub> = 150 °C	-	1.6		μC
I <sub>RRM</sub>	Reverse recovery current	(see <i>Figure 16</i> )	-	12.5		А

Table 8. Source drain diode

1. Pulse width limited by safe operating area.

2. Pulsed: pulse duration =  $300 \ \mu$ s, duty cycle 1.5%



### 2.1 Electrical characteristics (curves)

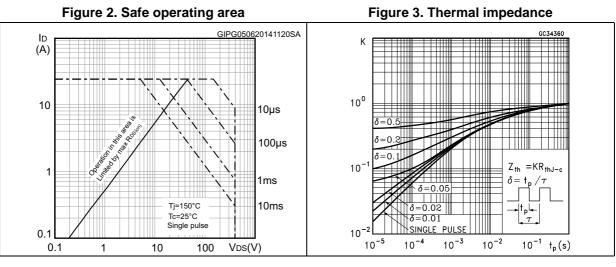
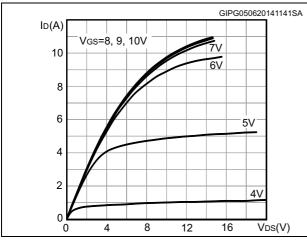
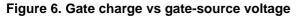


Figure 4. Output characteristics





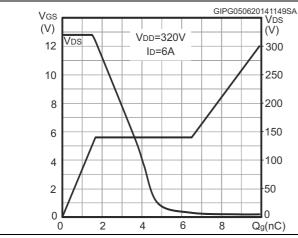


Figure 5. Transfer characteristics

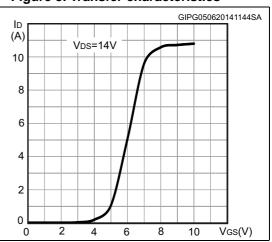
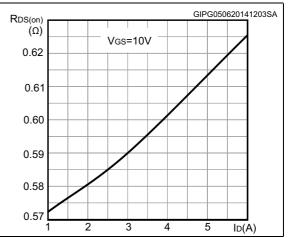


Figure 7. Static drain-source on-resistance





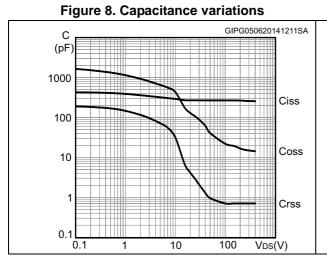


Figure 10. Normalized gate threshold voltage vs temperature

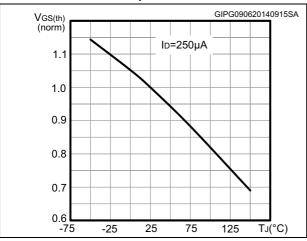
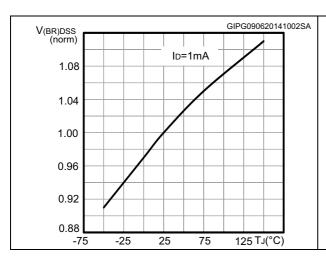


Figure 12. Normalized V<sub>(BR)DSS</sub> vs temperature



Electrical characteristics

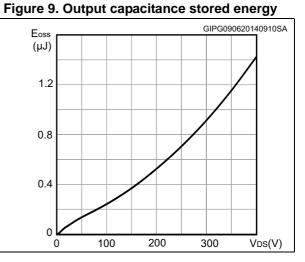


Figure 11. Normalized on-resistance vs temperature

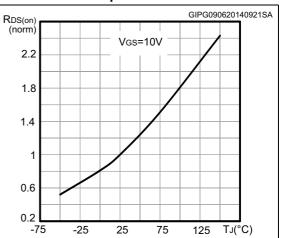
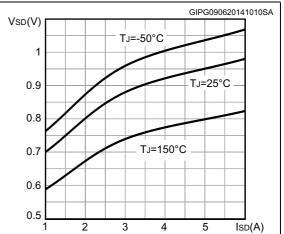


Figure 13. Source-drain diode forward characteristics





#### 3 **Test circuits**

Figure 14. Switching times test circuit for resistive load

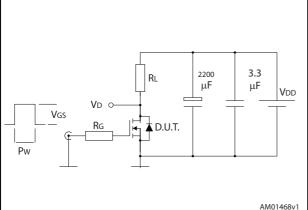


Figure 16. Test circuit for inductive load switching and diode recovery times

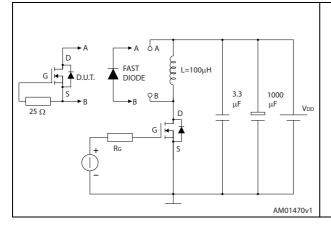


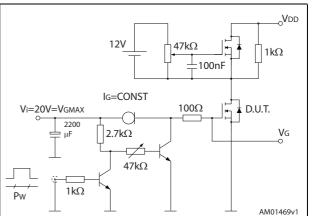
Figure 18. Unclamped inductive waveform

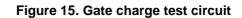
VD

ldм

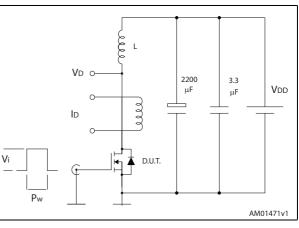
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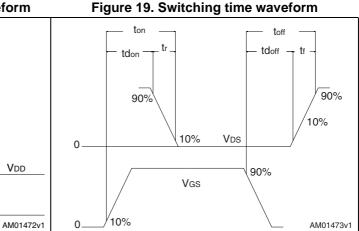
V(BR)DSS











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Vdd

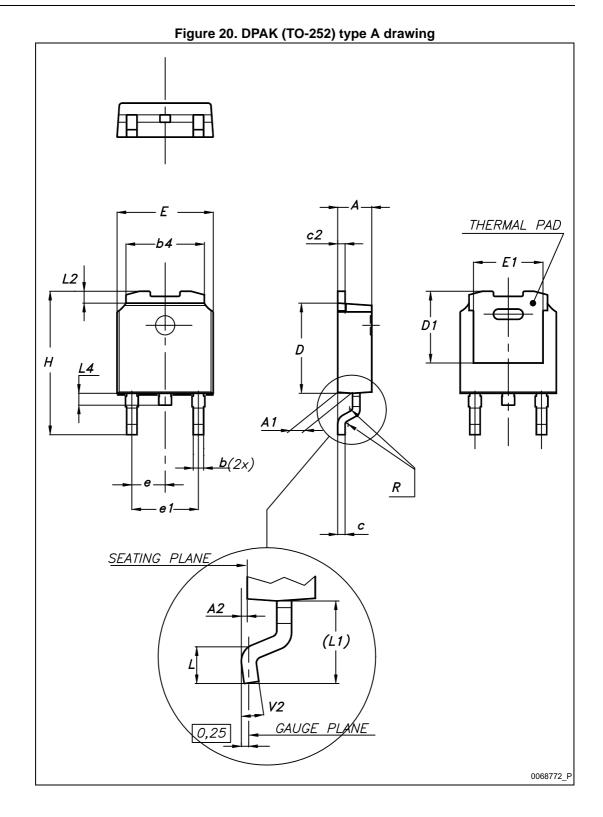


Vdd

### 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK<sup>®</sup> is an ST trademark.







Dim		mm	
Dim. —	Min.	Тур.	Max.
А	2.20		2.40
A1	0.90		1.10
A2	0.03		0.23
b	0.64		0.90
b4	5.20		5.40
с	0.45		0.60
c2 D	0.48		0.60
			6.20
D1		5.10	
E	6.40		6.60
E1		4.70	
е		2.28	
e1	4.40		4.60
Н	9.35		10.10
L	1.00		1.50
(L1)		2.80	
L2		0.80	
L4	0.60		1.00
R		0.20	
V2	0°		8°

Table 9. DPAK (TO-252) type A mechanical data



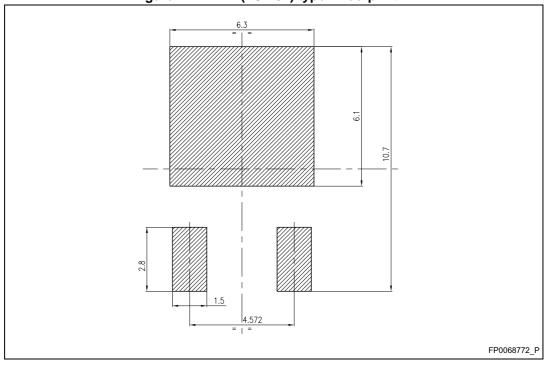


Figure 21. DPAK (TO-252) type A footprint <sup>(a)</sup>



a. All dimensions are in millimeters

### 5 Packaging mechanical data

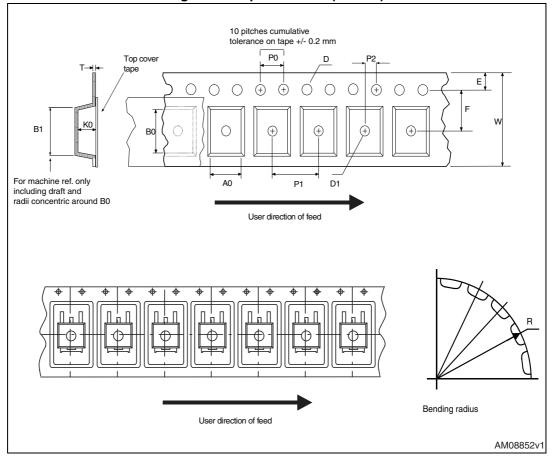


Figure 22. Tape for DPAK (TO-252)



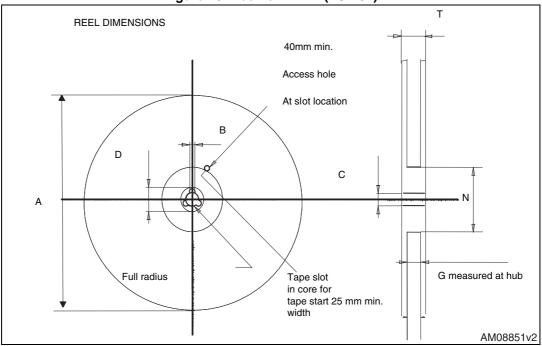


Figure 23. Reel for DPAK (TO-252)

Таре			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.	Dim.	Min.	Max.
A0	6.8	7	Α		330
B0	10.4	10.6	В	1.5	
B1		12.1	С	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
E	1.65	1.85	N	50	
F	7.4	7.6	Т		22.4
K0	2.55	2.75			
P0	3.9	4.1		Base qty.	2500
P1	7.9	8.1		Bulk qty.	2500
P2	1.9	2.1			
R	40				
Т	0.25	0.35			
W	15.7	16.3			



## 6 Revision history

Date	Revision	Changes	
09-Jan-2014	1	First release.	
18-Jun-2014	2	<ul> <li>Modified: title</li> <li>Modified: values in <i>Table 4</i></li> <li>Modified: R<sub>DS(on)</sub> and I<sub>DSS</sub> (test conditions) in <i>Table 5</i></li> <li>Modified: the entire typical values in <i>Table 6</i>, 7 and 8</li> <li>Added: <i>Table 8</i></li> <li>Added: Section 2.1: Electrical characteristics (curves)</li> <li>Updated: Section 4: Package mechanical data</li> <li>Minor text changes</li> </ul>	

Table 11. Document revision history



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